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APPLICATION NO.	FI	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/613,541 07/07/2000		07/07/2000	Atsushi Nakamura	501.34189R00	9061
20457	7590	09/16/2005		EXAM	INER
	•	RY, STOUT & KI	WILLIAMS, AI	WILLIAMS, ALEXANDER O	
1300 NORTH SEVENTEENTH STREET SUITE 1800			ART UNIT	PAPER NUMBER	
ARLINGTON, VA 22209-3873				2826	

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Please find below and/or attached an Office communication concerning this application or proceeding.

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,		Application No.	Applicant(s)			
		09/613,541	NAKAMURA ET AL.			
	Office Action Summary	Examiner	Art Unit			
		Alexander O. Williams	2826			
Period fo	The MAILING DATE of this communication app or Reply	pears on the cover sheet wi	th the correspondence address -			
WHIC - Exte after - If NC - Failt Any	IORTENED STATUTORY PERIOD FOR REPL' CHEVER IS LONGER, FROM THE MAILING Dansions of time may be available under the provisions of 37 CFR 1.1 or SIX (6) MONTHS from the mailing date of this communication. Diperiod for reply is specified above, the maximum statutory period or the toreply within the set or extended period for reply will, by statute reply received by the Office later than three months after the mailing led patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNION (36(a). In no event, however, may a rewill apply and will expire SIX (6) MON, cause the application to become AB	CATION. eply be timely filed THS from the mailing date of this communical ANDONED (35 U.S.C. § 133).			
Status						
1)⊠	Responsive to communication(s) filed on 4/7/0	<u> 5 -8/17/05</u> .	•			
2a) <u></u> ☐	2a) This action is FINAL . 2b) This action is non-final.					
3)□	Since this application is in condition for allowar	•	•	s is		
	closed in accordance with the practice under E	Ex parte Quayle, 1935 C.D	. 11, 453 O.G. 213.			
Disposit	ion of Claims					
5)□ 6)⊠	Claim(s) <u>1-6,8-29,32-38 and 91-101</u> is/are penda) Of the above claim(s) is/are withdray Claim(s) is/are allowed. Claim(s) <u>1-6,8-29,32-38 and 91-101</u> is/are rejected to.	wn from consideration.				
8)□	Claim(s) are subject to restriction and/o	r election requirement.				
Applicat	ion Papers					
10)	The specification is objected to by the Examine The drawing(s) filed on is/are: a) accomplicant may not request that any objection to the Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine	epted or b) objected to l drawing(s) be held in abeyan ion is required if the drawing(ice. See 37 CFR 1.85(a). (s) is objected to. See 37 CFR 1.12	• •		
Priority (under 35 U.S.C. § 119					
a)	Acknowledgment is made of a claim for foreign All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority document application from the International Bureausee the attached detailed Office action for a list	s have been received. s have been received in A rity documents have been u (PCT Rule 17.2(a)).	pplication No. <u>08/570,646</u> . received in this National Stage			
Attachmen	rt(s)	·				
2) Notice (3) Information	ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) er No(s)/Mail Date	Paper No(s	summary (PTO-413) s)/Mail Date nformal Patent Application (PTO-152) 			

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Serial Number: 09/613541 Attorney's Docket #: 501.34189R))

Filing Date: 7/7/2000; The certified copy has been filed in parent Application No.

08/570646, filed on 5/25/1995 and 12/20/94.

Applicant: Nakamura et al.

Examiner: Alexander Williams

Applicant's Third Supplement Amendment, filed 8/17/05 has been acknowledged.

Applicant's Second Supplement Amendment, filed 7/19/05 has been acknowledged.

Applicant's Supplemental Amendment, filed 7/13/05 has been acknowledged.

Applicant's Amendment and two Declarations, filed 4/7/05 has been acknowledged.

Claim 7, 31 and 39-90 are cancelled.

The disclosure is objected to because of the following informalities: The related application information should be updated.

Appropriate correction is required.

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

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This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(f) or (g) prior art under 35 U.S.C. 103(a).

Claims 1 to 6, 8 to 29, 32 to 38 and 91 to 101 are rejected under 35 U.S.C. 103(a) as being unpatentable over Hinrichsmeyer et al. (U.S. Patent # 4,996,587) in view of Kondo et al. (U.S. Patent # 5,438,478)

For example, in claim 1 and similar claims 8, 10, 11, 14, 22, 91, 96 and 22, Hinrichsmeyer et al. (figures 1 to 7) specifically **figure 5** show a semiconductor device **20** comprising: a rigid substrate **10** having a first main surface and a second main surface opposite to the first main surface; a semiconductor pellet **19** mounted on the first main surface **23** of the rigid substrate, the semiconductor pellet having a plurality of semiconductor circuit elements (inherit) and a plurality of bonding pads **21**; a plurality of electrode pads formed on the second main surface of the rigid substrate; and a plurality of bonding wires **22** for electrically connecting the bonding pads of the semiconductor pellet with the electrode pads; wherein the semiconductor pellet is mounted facedown on the rigid substrate, the rigid substrate has slits **13** that extend from the first main surface to the second main surface and expose the bonding pads of the semiconductor pellet, the bonding wires extend through the slits in the rigid substrate to connect the bonding pads and the electrode pads and bump electrodes **25** are formed on said electrode pads.

Hinrichsmeyer et al. fail to explicitly show a rigid substrate formed by glass fibers impregnated with epoxy or polyimide resins.

Kondo et al. is cited for showing electronic component carriers. Specifically, Kondo et al. (figures 1 to 32) specifically figures 3 and 4 discloses a semiconductor device comprising: a rigid substrate 10 having a first main surface and a second main surface opposite to the first main surface; a semiconductor pellet 34 mounted within the rigid substrate, the semiconductor pellet having a plurality of semiconductor circuit elements (inherit) and a plurality of bonding pads (inherent); a plurality of electrode

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pads 28 formed on the second main surface of the rigid substrate; and a plurality of bonding wires 38 for electrically connecting the bonding pads of the semiconductor pellet with the electrode pads; wherein the semiconductor pellet is facedown in the rigid substrate, the rigid substrate has slits 12 that extend from the first main surface to the second main surface and expose the bonding pads of the semiconductor pellet, the bonding wires connecting the bonding pads and the electrode pads; and the rigid substrate formed by glass fibers impregnated with epoxy or polyimide resins for the purpose of enhancing the lifetime and reliability of a connection between a chip and a substrate.

(2) FIG. 3 schematically shows a first embodiment of the electronic component carrier according to the invention. FIG. 3, a printed wiring substrate 10 (thickness: 0.2 mm) formed by laminating copper foils onto both surfaces of a base material, which is obtained by impregnating a glass cloth with bismaleimide triazine resin, is provided at its central portion with a cavity 12 for mounting a given electronic component (e.g. semiconductor elément) and through-holes 14 are formed in the The inner surface of the substrate at given positions. substrate constituting the through-hole 14 is first subjected to a copper plating and then to a nickel plating and further to a gold plating. On the other hand, a lead frame 20 composed of a given metal foil (e.g., MF202-H made by Mitsubishi Electric Corporation, thickness: 0.15 mm) is disposed on an upper surface of the substrate 10 in place, and a top portion of each inner lead 22 is subjected to a silver plating for the connection to a gold wire as mentioned later. Furthermore, an outer lead 24 is extended outward from the respective inner lead 22 in the lead frame so as to connect to the other circuit or the like in a given assembling operation. The printed wiring substrate 10 and the lead frame 20 are joined to each other through a layer 26 of an adhesive composed of an epoxy resin. The electronic component carrier shown in FIG. 3 corresponds to multipin-type QFP and is shown as only one piece of the lead frame for multiple pattern. As the printed wiring substrate, use may be made of a laminate of glass cloths each impregnated with a heatresistant insulating resin such as epoxy resin, polyimide resin, Teflon (trade name) or the like, ceramic laminate and so on in addition to the above laminate covered at both surfaces with copper foils. In the embodiment of FIG. 3, a ground ring 28 for earth is connected to the conductor pattern formed on the rear surface side of the substrate 10 through the through-hole to

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reduce lead inductance, whereby the degree of freedom in the pattern design for the substrate 10 is improved.

(3) FIG. 4 shows a sectional view taken along a line IV--IV of FIG. 3. As shown in FIG. 4, the inner lead 22 of the lead frame 20 or the neighborhood thereof is joined to the front surface of the printed wiring substrate 10 through the adhesive layer 26 formed in place around the cavity 12. In this case, the substrate 10 is subjected to C-face working in order to improve the shapability in mold. The adhesive layer 26 is composed of a thermosetting resin having a high heat resistance such as epoxy resin, polyimide resin, triazine resin or the like. When the thermosetting resin is used as an adhesive, it is desirable that an amount of ionic impurities such as Cl.sup.- and so on is low (not more than 10 ppm).

In claim 2, Hinrichsmeyer et al. showing wherein the bonding pads **21** are arranged at the periphery of the semiconductor pellet and the slits **13** are formed along the directions of rows of the bonding pads.

In claim 3, Hinrichsmeyer et al. show wherein the electrode pads are located on both sides of the slits **13**.

For example, in claim 26, Hinrichsmeyer et al. (figures 1 to 7) specifically figure 5 show a semiconductor device 20 comprising: a semiconductor pellet 19 of a quadrilateral shape having bonding pads 21 formed in a main surface thereof, said semiconductor pellet having a first pair of opposed edges extending in a first direction and a second pair of opposed edges extending in a second direction which intersects said first direction, wherein at least some of said bonding pads 21 extend in said first direction to form a row bonding pads; a substrate 10 having a first surface, a second surface opposite to said first surface, electrode pads formed on said second surface and a slit 13 passing through said substrate from said first surface to said second surface and extending in said first direction, said semiconductor pellet being disposed on said first surface of said substrate such that said main surface of said semiconductor pellet is faced to said first surface of said substrate and said bonding pads are arranged in said slit in a plan view, said electrode pads including first second electrode pads arranged at the other side of said slit in said second direction; bonding wires 22 electrically connecting said electrode pads of said substrate with said bonding pads of said semiconductor pellet via said slit, said bonding wires including first bonding wires connected to said first electrode pads and second bonding wires connected to said

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second electrode pads; bump electrodes 25 being disposed on said second surface of said substrate and being electrically connected to said electrode pads of said substrate, said bump electrodes including first bump electrodes electrically connected to said first electrode pads arranged at said one side of said slit and second bump electrodes electrically connected to said second electrode pads and arranged at the other side of said slit; and a resin sealing body 28 sealing said bonding wires and said main surface of said semiconductor pellet exposed from said slit. The combination with Kondo et al., as detailed above, show the ridid substrate is formed by glass fibers impregnated with polyimide resin. Hinrichsmeyer et al. fail to explicitly show each of said first and second bump electrodes being arranged in both said first and second directions to form a matrix in said plain view, respectively. However, Hinrichsmeyer et al. (figure 4) does discloses each of said first and second external card connection means 17 being arranged in both said first and second directions to form a matrix in said plain view of the second surface 12 of the substrate 10, respectively. The external card connection means 17 including first external card connection means electrically connected to said first electrode pads 17a arranged at said one side of said slit and second external card connection means electrically connected to said second electrode pads 17a and arranged at the other side of said slit 13. It is understood to one of ordinary skill in the art, viewing figures 4 and 5, that the solder pad 25 (in which can be considered bumps or balls) on the second surface 12 of the substrate 10 are directly connected to the pattern, row or matrix of external card connection means 17 shown in the plan view of figure 4. Therefore, it would be obvious to one of ordinary skill in the art to use the teaching of Hinrichsmeyer et al.'s external card connection means and the solder pads to be the claimed bump electrodes to form a matrix as claimed by Applicant for the purpose of providing a electrical connection for the package having a minimum thickness and good thermal qualities whose production can be simplified.

In claim 27, Hinrichsmeyer et al. show said row of bonding pads **21** is disposed at a substantially central area between said first pair of opposed edges of said semiconductor pellets.

In claim 28, Hinrichsmeyer et al. show wherein said semiconductor pellet **19** has a rectangular shape, and wherein said first pair of opposed edges correspond to a pair of longer edges and said second pair of opposed edges correspond to a pair of shorter edges.

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In claim 29, Hinrichsmeyer et al. show wherein said slit 13 tapered so that an opening on said second surface of substrate is greater than an opening on said first surface of said substrate.

In claim 34, Hinrichsmeyer et al. show wherein said substrate has land portions 12 and conductors 12 formed between said land portions and said electrode pads 21, wherein a width of each of said lead portions is larger than a width of each of said conductors, wherein said land portions, said conductors and said electrode pads are integrally formed with one another on said second surface of said substrate, and wherein said bump electrodes are disposed on said land portions, respectively

In claim 35, Hinrichsmeyer et al. show wherein said substrate **10** is formed of a single layer structure that has conductors arranged only on said second surface of said substrate.

Initially, and with respect to claim 33, note that a "product by process" claim is directed to the product per se, no matter how actually made, In re Hirao, 190 USPQ 15 at 17 (footnote 3). See also In re Brown, 173 USPQ 685; In re Luck, 177 USPQ 523; In re Wertheim, 191 USPQ 90 (209 USPQ 554 does not deal with this issue); In re Fitzgerald, 205 USPQ 594, 596 (CCPA); In re Marosi et al., 218 USPQ 289 (CAFC); and most recently, In re Thorpe et al., 227 USPQ 964 (CAFC, 1985) all of which make it clear that it is the final product per se which must be determined in a "product by process" claim, and not the patentability of the process, and that, as here, an old or obvious product produced by a new method is not patentable as a product, whether claimed in "product by process" claims or not. Note that Applicant has burden of proof in such cases as the above case law makes clear.

As to the grounds of rejection under section 103, see MPEP § 2113.

Therefore, it would be obvious to one of ordinary skill at the time of the invetion to use Kondo et al's glass impregnated with epoxy or polyimide resin in the substrate and features to modify Hinrichsmeyer et al.'s substrate and features for the purpose of enhancing the lifetime and reliability of a connection between a chip and a substrate.

Response

Applicant's arguments filed 10/20/03 have been fully considered, but are moot in view of the new grounds of rejections detailed above.

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The listed references are cited as of interest to this application, but not applied at this time.

Field of Search	Date
U.S. Class and subclass:	5/14/03
257/778,777,780,737,784,673,696,698,680,773	1/19/05
	9/14/05
Other Documentation:	5/14/03
foreign patents and literature in	1/19/05
257/778,777,780,737,784,673,696,698,680,773	9/14/05
Electronic data base(s):	5/14/03
U.S. Patents EAST	1/19/05
·	9/14/05

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Alexander O Williams whose telephone number is (571) 272 1924. The examiner can normally be reached on M-F 6:30-7:00PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nathan Flynn can be reached on (571) 272 1915. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Alexander O Williams Primary Examiner Art Unit 2826

AOW 9/14/05